

**200V, 70A N-CHANNEL POWER MOSFET****GENERAL DESCRIPTION**

The SGP20HR24T uses advanced SGT technology and design to provide excellent  $R_{DS(on)}$  with low gate charge.

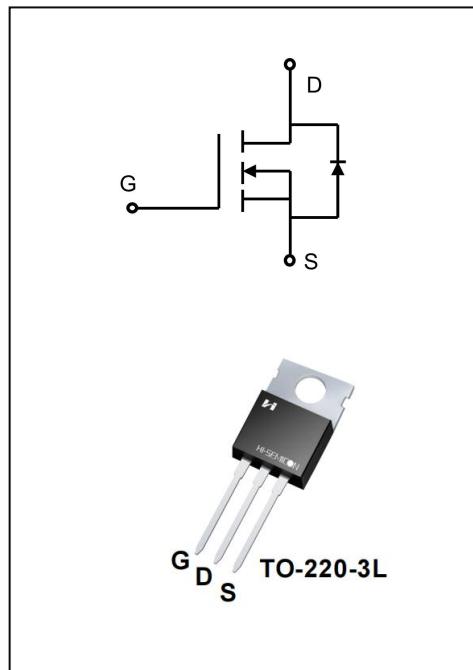
It can be used in a wide variety applications.

**Features**

- ◆  $V_{DS}=200V$ ,  $I_D=70A$
- ◆  $R_{DS(on)}$   
TYP:  $19.5m\Omega$  @  $V_{GS}=10V$

**Applications**

- ◆ Motor control and drive
- ◆ Battery management System
- ◆ UPS (Uninterruptible Power Supplies)

**ORDERING INFORMATION**

Part No.	Package	Marking	Material	Packing
SGP20HR24T	TO-220-3L	SGP20HR24T	Pb Free	Tube

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	200	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current	I <sub>D</sub>	70	A
T <sub>C</sub> = 100°C	I <sub>D</sub>	45	
Drain Current Pulsed(Note 1)	I <sub>DM</sub>	280	A
Power Dissipation(T <sub>C</sub> =25°C)	P <sub>D</sub>	208	W
Single Pulsed Avalanche Energy (Note 2)	E <sub>AS</sub>	420	mJ
Operation Junction Temperature Range	T <sub>J</sub>	-55~+150	°C
Storage Temperature Range	T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	TL	260	°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.6	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62.5	°C/W

**ELECTRICAL CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	200	--	--	V
Drain-Source Leakage Current	I <sub>DS</sub>	V <sub>DS</sub> =200V, V <sub>GS</sub> =0V	--	--	1.0	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	3.0	3.9	5.0	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =45A	--	19.5	24	mΩ
<b>Dynamic Characteristics</b>						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V; f=1.0MHZ	--	5.0	--	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =100V V <sub>GS</sub> =0V f=1.0MHZ	--	2673	--	pF
Output Capacitance	C <sub>oss</sub>		--	232	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	9.7	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =100V, V <sub>DS</sub> =10V R <sub>G</sub> =2.5Ω, I <sub>D</sub> =45A (Note 3.4)	--	21.5	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	81.2	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	32.6	--	
Turn-off Fall Time	t <sub>f</sub>		--	10.1	--	

Total Gate Charge	$Q_g$	$V_{DS}=100V, I_D=45A$ $V_{GS}=10V$ (Note 3.4)	--	35.5	--	nC
Gate-Source Charge	$Q_{gs}$		--	20.7	--	
Gate-Drain Charge	$Q_{gd}$		--	4.3	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	70	A
Pulsed Source Current	$I_{SM}$		--	--	280	
Diode Forward Voltage	$V_{SD}$	$I_s=45A, V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	$T_{rr}$	$I_F=45A, V_R=10V,$ $dI/dt=100A/\mu s$	--	128	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	603	--	nC

1. Pulse width limited by maximum junction temperature

2. L=0.5mH,  $V_{DD}=100V, V_{GS}=10V, R_G=25\Omega$ , starting  $T_J=25^\circ$ 3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ 

4. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. Output Characteristics

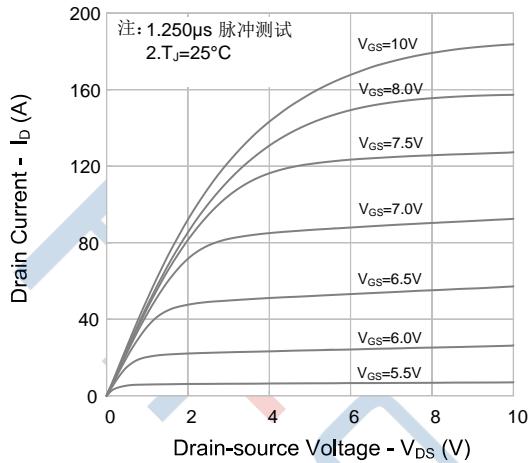


Figure 2. Transfer Characteristics

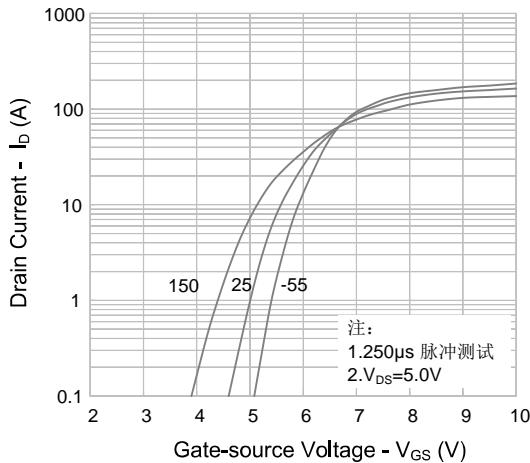


Figure 3. On-resistance vs. Drain Current

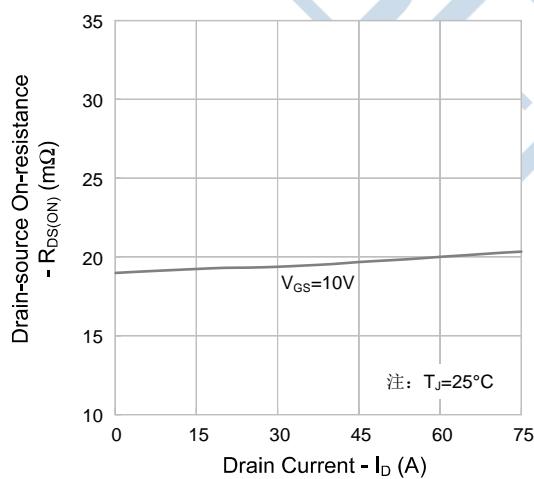


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

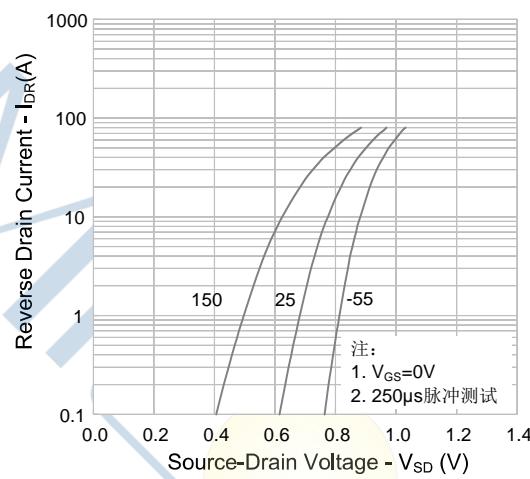


Figure 5. Capacitance Characteristics

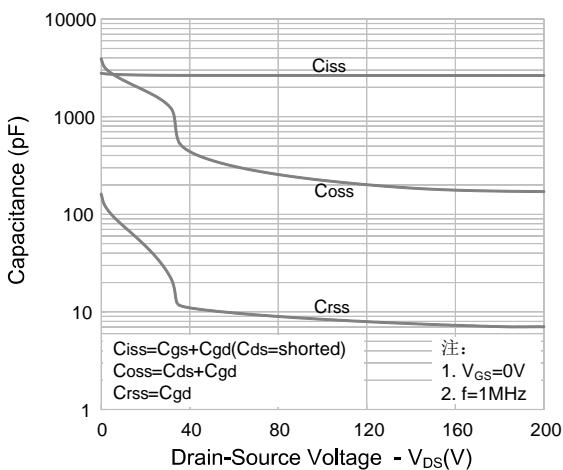
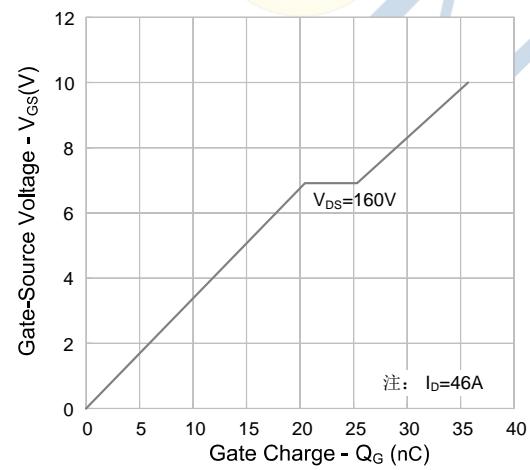


Figure 6. Gate Charge Characteristics



## Typical Performance Characteristics

Figure 7. Breakdown Voltage vs. Temperature Characteristics

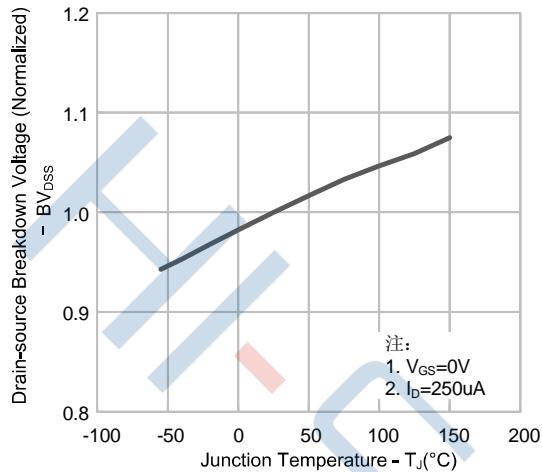


Figure 8. On-resistance vs. Temperature Characteristics

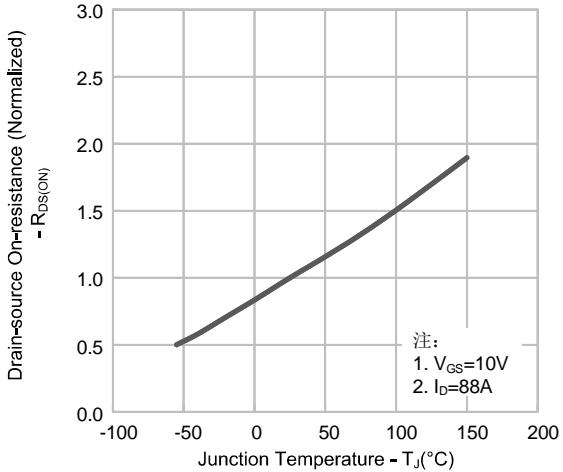
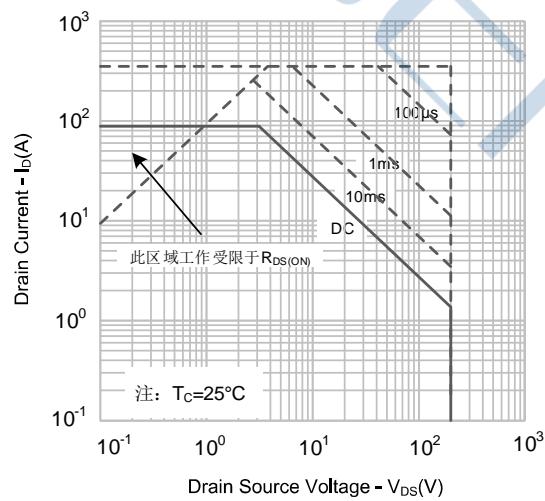
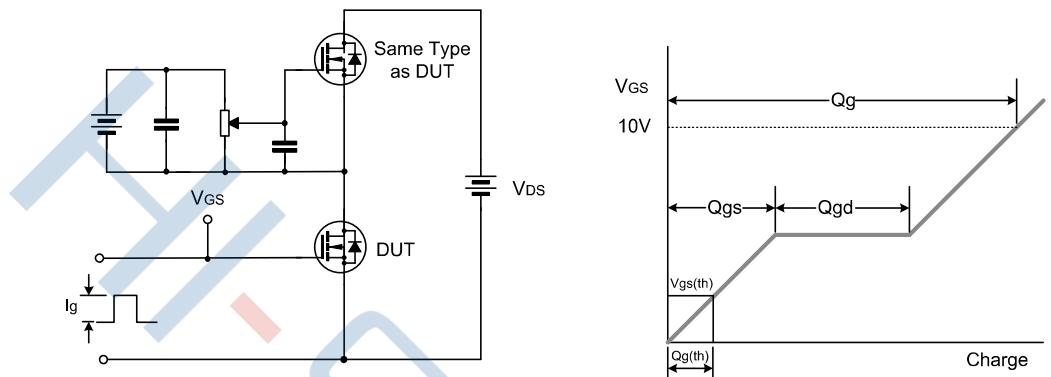
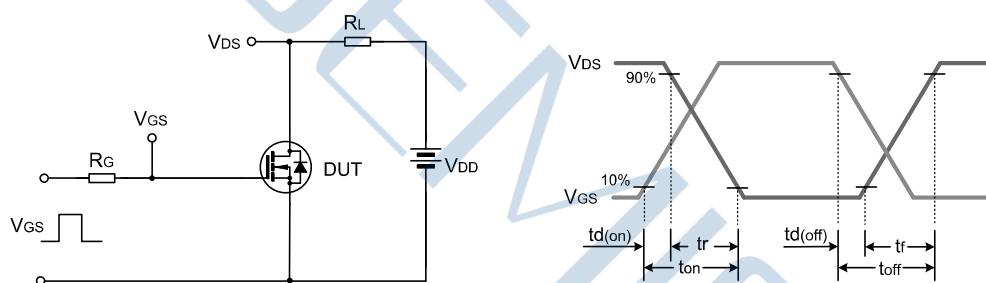


Figure 9. Max. Safe Operating Area

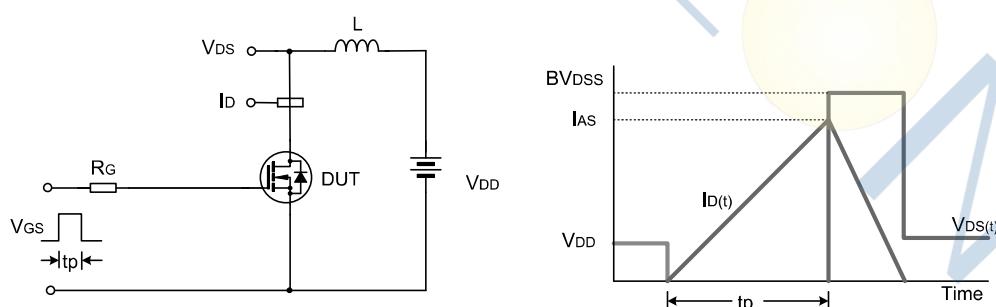


**Test Circuit**

Gate Charge Test Circuit &amp; Waveform

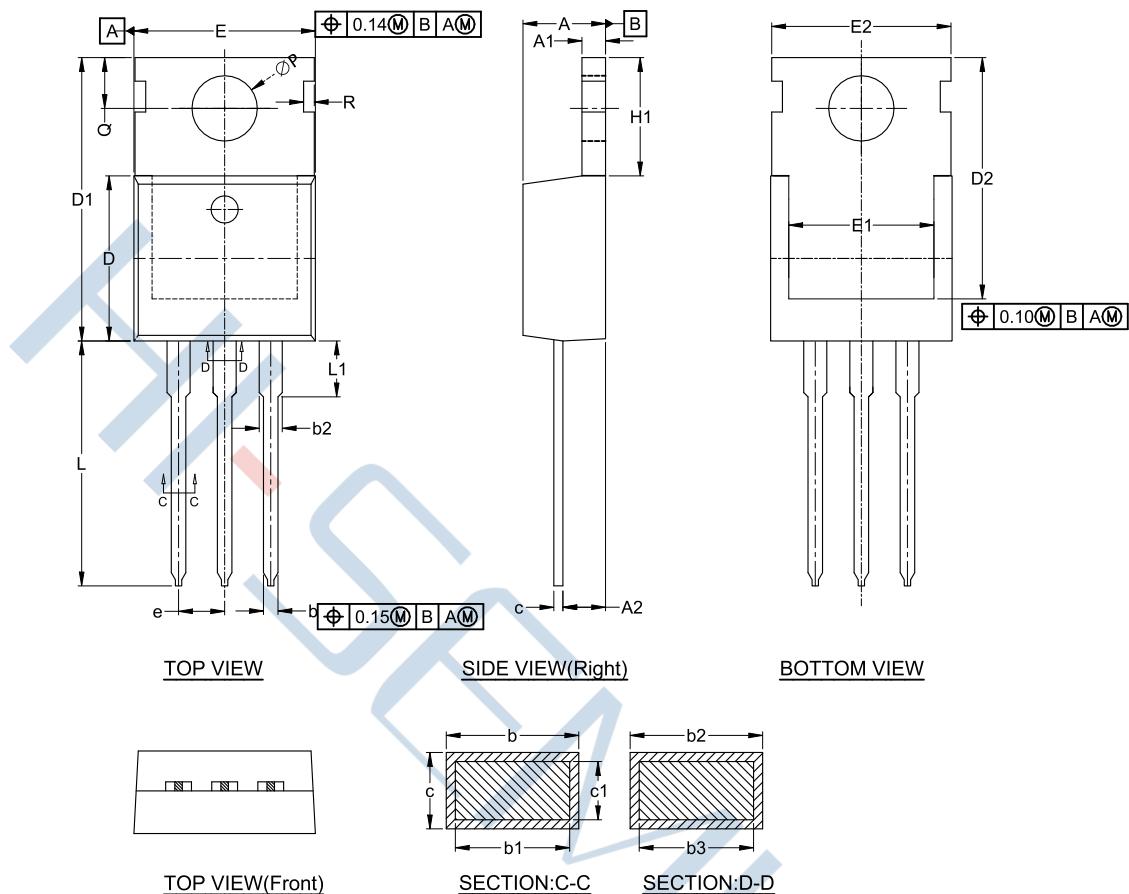


Resistive Switching Test Circuit &amp; Waveform



Unclamped Inductive Switching Test Circuit &amp; Waveform

**Package Dimensions of TO-220-3L**



DIM SYMBOL	MIN.	NOM.	MAX.
A	4.450	4.550	4.650
A1	1.240	1.340	1.440
A2	2.250	2.350	2.450
b	0.740	0.840	0.940
b1	0.700	0.800	0.900
b2	1.210	1.310	1.410
b3	1.170	1.270	1.370
c	0.440	0.540	0.640
c1	0.400	0.500	0.600
D	9.000	9.100	9.200
D1	15.420	15.620	15.820
D2	13.100	13.300	13.500
E	9.900	10.000	10.100
E1	7.800	8.000	8.200
E2	9.680	9.880	10.080
e	2.540 BSC.		
H1	6.420	6.520	6.620
L	13.300	13.500	13.700
L1	2.880	3.080	3.280
ØP	3.500	3.600	3.700
Q	2.600	2.800	3.000
R	0.590 REF.		

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